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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Yoko IKEDA *et al.*

Serial No.: 09/452,149

Filed: 1 December 1999

For: INSPECTING METHOD, INSPECTING SYSTEM, AND  
METHOD FOR MANUFACTURING ELECTRONIC DEVICES

Art Unit: 2623

Examiner: Virginia M. KIBLER

RECEIVED

JUN 30 2003

Technology Center 2600

**AMENDMENT**

Honorable Commissioner for Patents  
Washington, D.C. 20231

27 June 2003

Sir:

In response to the Office Action mailed 27 March 2003 in connection with the  
above-identified application, Applicant respectfully submits the following  
amendments and remarks.